

Specification for

**Harmonized system of  
quality assessment for  
electronic  
components —  
Blank detail  
specification —**

**MOS ultra-violet light erasable  
electrically programmable read only  
memories silicon monolithic circuits**

Amendments issued since publication

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# National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Committee. It is identical with CENELEC Electronic Components Committee (CECC) 90113:1986 “*Harmonized system of quality assessment for electronic components. Blank detail specification: MOS ultra-violet light erasable electrically programmable read only memories silicon monolithic circuits*”.

This standard is a harmonized specification within the CECC System.

**Terminology and conventions.** The text of the CECC specification has been approved as suitable for publication as a British Standard without deviation. Some terminology and certain conventions are not identical with those used in British Standards; attention is drawn especially to the following.

The comma has been used as a decimal marker. In British Standards it is current practice to use a full point on the baseline as the decimal marker.

**Cross-references.** The British Standard which implements CECC 00100 is BS 9000: “*General requirements for a system for electronic components of assessed quality*” Part 2:1983 “*Specification for national implementation of CECC basic rules and rules of procedure*”.

| International Standards <sup>a</sup> | Corresponding British Standards                                                                                                                                             |
|--------------------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| IEC 68-2-30:1980                     | BS 2011 <i>Basic environmental testing procedures — Part 2.1 Db:1981 Test Db and guidance. Damp heat cyclic (12 + 12 hour cycle)</i><br>(Identical)                         |
| IEC 617-12:1983                      | BS 3939 <i>Guide for graphical symbols for electrical power, telecommunications and electronics diagrams — Part 12:1985 Binary logic elements</i><br>(Identical)            |
| CECC 90000:1985                      | BS CECC 90000:1985 <i>Harmonized system of quality assessment for electronic components. General specification: monolithic integrated circuits</i><br>(Identical)           |
| CECC 90100:1986                      | BS CECC 90100:1986 <i>Harmonized system of quality assessment for electronic components. Sectional specification: digital monolithic integrated circuits</i><br>(Identical) |

<sup>a</sup> Undated in text.

The Technical Committee has reviewed the provisions of IEC 747, to which reference is made in the text, and has decided that they are acceptable for use in conjunction with this standard.

**Scope.** This standard lists the ratings, characteristics and inspection requirements when shall be included as mandatory requirements in accordance with BS CECC 90100 in any detail specification for these devices.

**Detail specification layout.** The front page layout of detail specifications released to BS CECC family or blank detail specifications will be in accordance with BS 9000 Circular letter NO. 15.

A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

**Compliance with a British Standard does not of itself confer immunity from legal obligations.**

## Summary of pages

This document comprises a front cover, an inside front cover, pages i and ii, the CECC title page, pages ii to iv, pages 1 to 20 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

English version

Harmonized System of Quality Assessment for  
Electronic Components

BLANK DETAIL SPECIFICATION:  
MOS ULTRA-VIOLET LIGHT  
ERASABLE  
ELECTRICALLY PROGRAMMABLE  
READ ONLY  
MEMORIES SILICON MONOLITHIC  
CIRCUITS

Système Harmonisé d'Assurance de la Qualité  
des Composants Electroniques

SPECIFICATION PARTICULIERE CADRE:

MEMOIRES MORTES MOS A  
CIRCUITS INTEGRES  
EFFAÇABLES AUX UV ET  
PROGRAMMABLES  
ELECTRIQUEMENT

Harmonisiertes Gütebestätigungssystem für  
Bauelemente der Elektronik

VORDRUCK FÜR  
BAUARTSPEZIFIKATION:  
INTEGRIERTE UV LÖSCHBARE  
ELEKTRISCH  
PROGRAMMIERBARE MOS  
FESTWERT-SPEICHER-  
SCHALTUNGEN



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Issue  
Edition  
Ausgabe

## CECC 90113

1986

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## Foreword

The CENELEC Electronic Components Committee (CECC) is composed of those member countries of the European Committee for Electrotechnical Standardization (CENELEC) who wish to take part in a harmonized System for electronic components of assessed quality.

The object of the System is to facilitate international trade by the harmonization of the specifications and quality assessment procedures for electronic components, and by the grant of an internationally recognized Mark, or Certificate, of Conformity. The components produced under the System are thereby accepted by all member countries without further testing.

This specification has been formally approved by the CECC, and has been prepared for those countries taking part in the System who wish to issue national harmonized specifications for MOS ULTRA-VIOLET LIGHT ERASABLE ELECTRICALLY PROGRAMMABLE READ ONLY MEMORIES SILICON MONOLITHIC CIRCUITS. It should be read in conjunction with the current regulations for the CECC System.

At the date of printing of this specification the member countries of the CECC are Austria, Belgium, Denmark, Finland, France, Germany, Ireland, Italy, the Netherlands, Norway, Portugal, Spain, Sweden, Switzerland, and the United Kingdom.

## Preface

This blank detail specification (BDS) was prepared by CECC WG9 "Integrated circuits".

It is based, wherever possible, on the Publications of the International Electrotechnical Commission and in particular on IEC 747: Semiconductor devices — Discrete devices and integrated circuits.

The text of this BDS was circulated to the CECC for voting in the documents indicated below and was ratified by the President of the CECC for printing as a CECC specification.

| Documents              | Date of Voting | Report on the voting   |
|------------------------|----------------|------------------------|
| CECC(Secretariat) 1336 | March 1983     | CECC(Secretariat) 1491 |
| CECC(Secretariat) 1603 | August 1984    | CECC(Secretariat) 1722 |

It is recognized that the layout proposed cannot be applied to all detail specifications based on this document. For instance, it may be preferable to indicate the limiting values in the form of a table when several similar devices appear in the same detail specification.

In accordance with the decision of the CECC Management Committee this specification is published initially in English and French. The German text will follow as soon as it has been prepared.

## General

The following information is given for guidance.

## Scope

This BDS relates to MOS ultra-violet light erasable electrically programmable read only memories in accordance with IEC 747: Semiconductor devices — Discrete devices and integrated circuits.

## Related documents

See **2.1** of CECC 90100 and **2.2** of CECC 90000

## Structure of Detail Specifications

Clause numbering of DS shall be in accordance with that of this document.

## Units, symbols and terminology

See **2.3** of CECC 90100 and **2.3** of CECC 90000

## Application of Quality Assessment Procedures

See 3 of CECC 90100 and CECC 90000.

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